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FIG. 3 is a cross-sectional view of a semiconductor device in accordance with the present invention. The device includes a P-substrate 16, a gate oxide 36, a poly gate 12, a source metal 10, a drain metal 11, a field oxide 40, a poly drain fieldplate 45, and a gate oxide 36. The device also includes a series of horizontal layers labeled N₁, N₂, ..., N_{k+1} and PB1, PB2, ..., PBk, which are connected to a common source metal 10. The layers N₁, N₂, ..., N_{k+1} are connected to a common drain metal 11. The layers PB1, PB2, ..., PBk are connected to a common source metal 10. The layers N₁, N₂, ..., N_{k+1} are connected to a common drain metal 11. The layers PB1, PB2, ..., PBk are connected to a common source metal 10. The layers N₁, N₂, ..., N_{k+1} are connected to a common drain metal 11. The layers PB1, PB2, ..., PBk are connected to a common source metal 10.

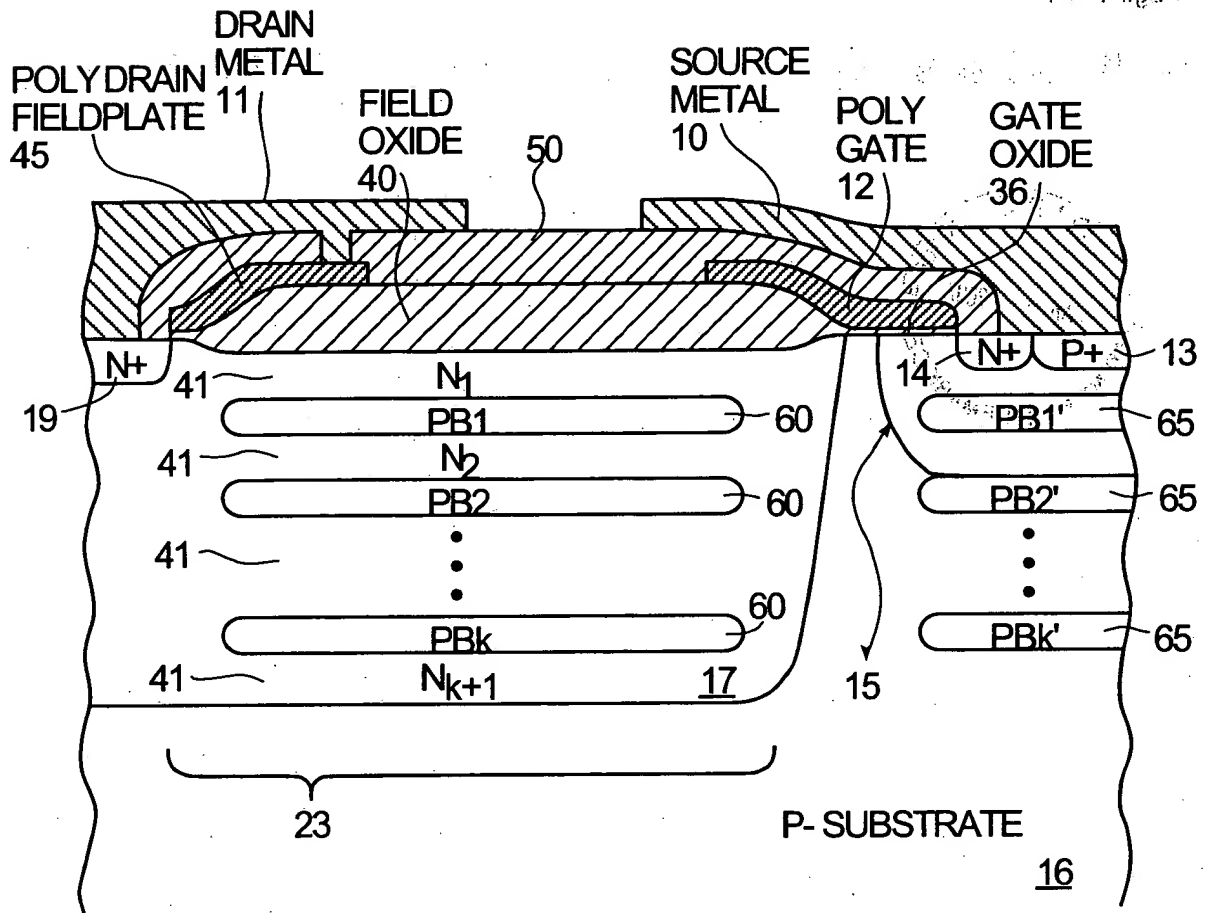


FIG. 3

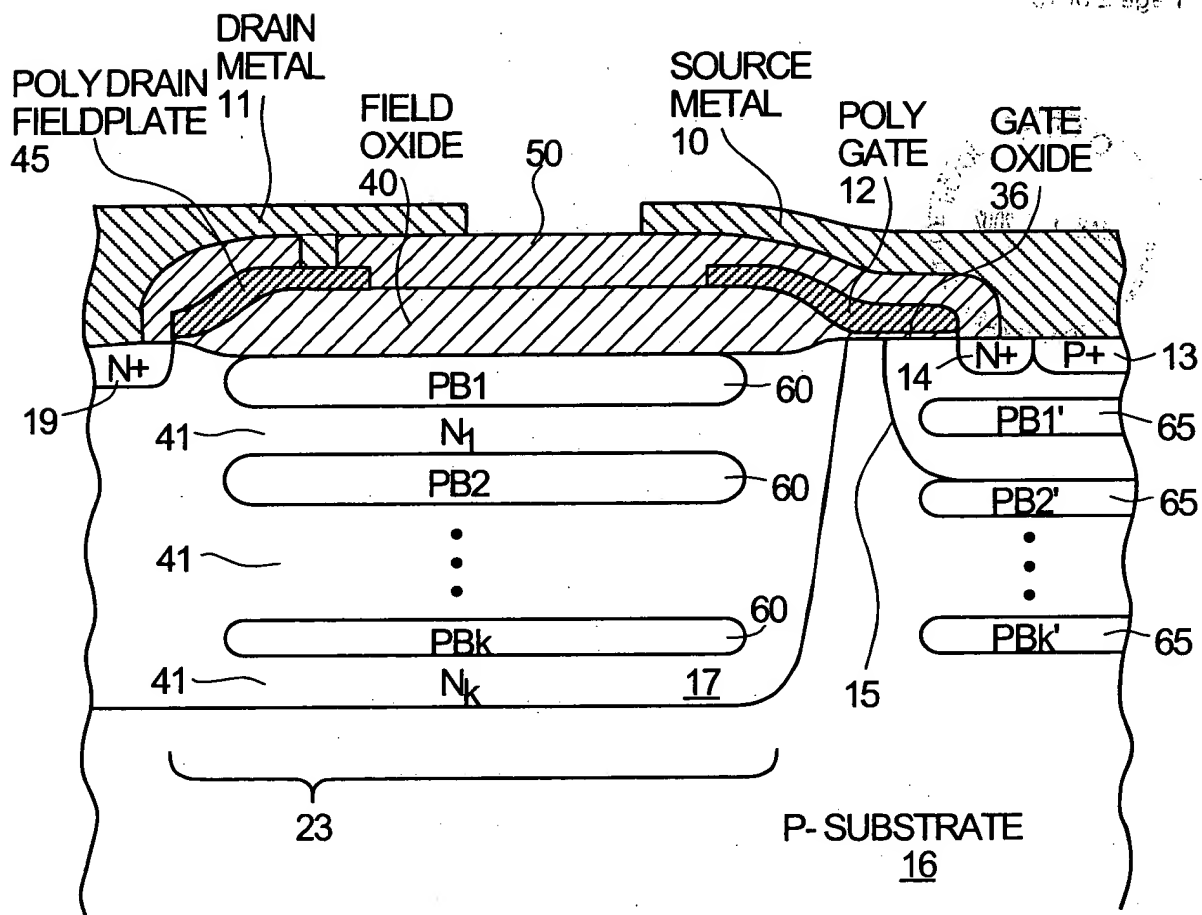


FIG. 4



FIG. 5



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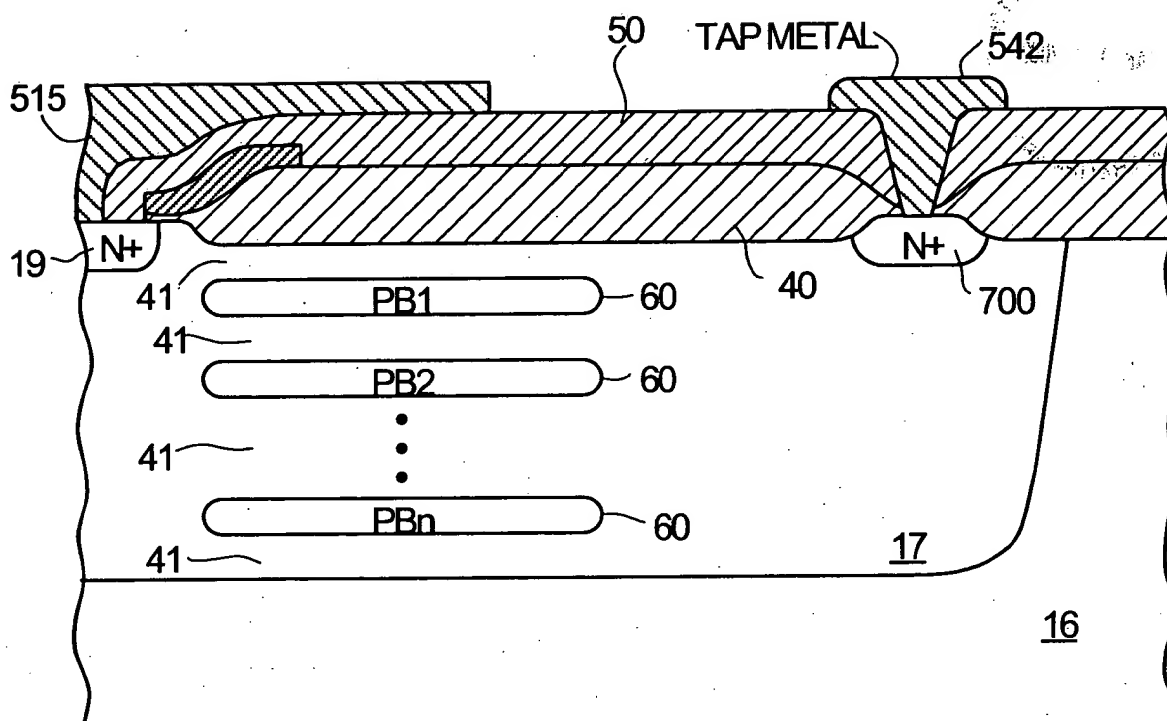
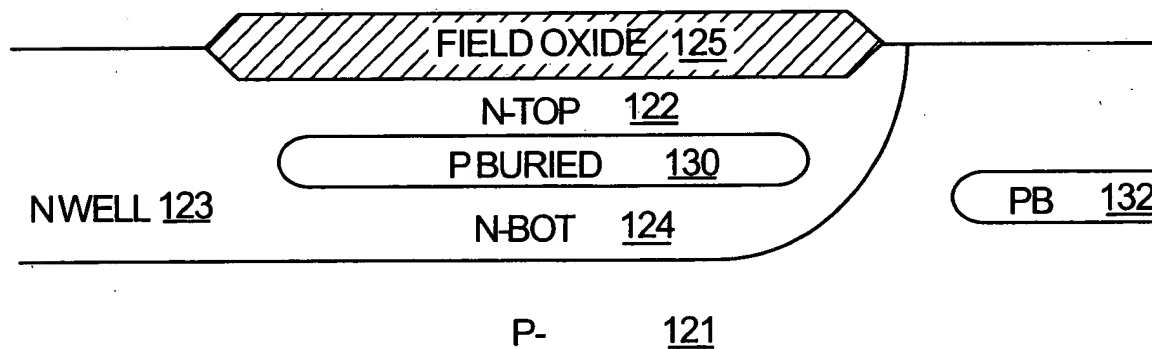
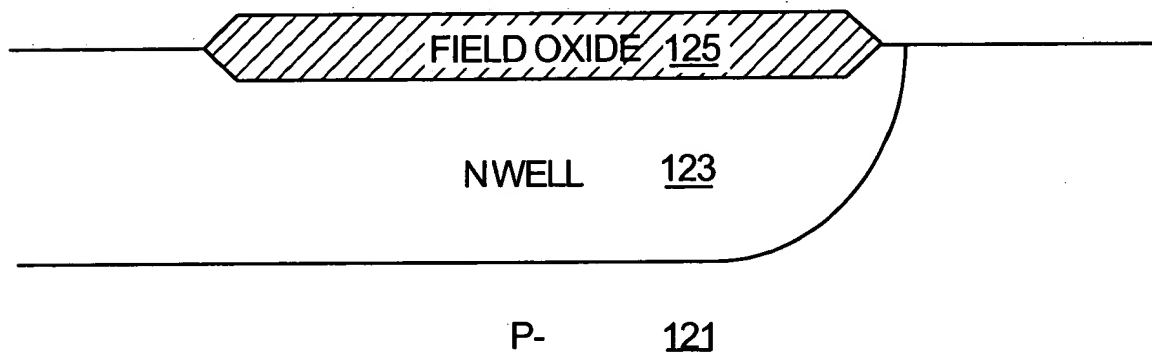
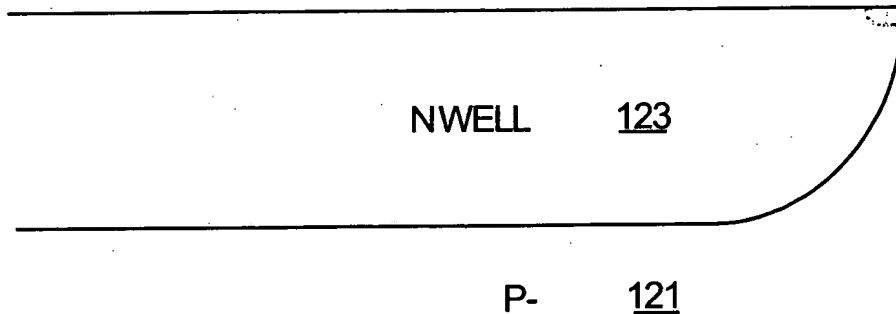


FIG. 10

[illegible]

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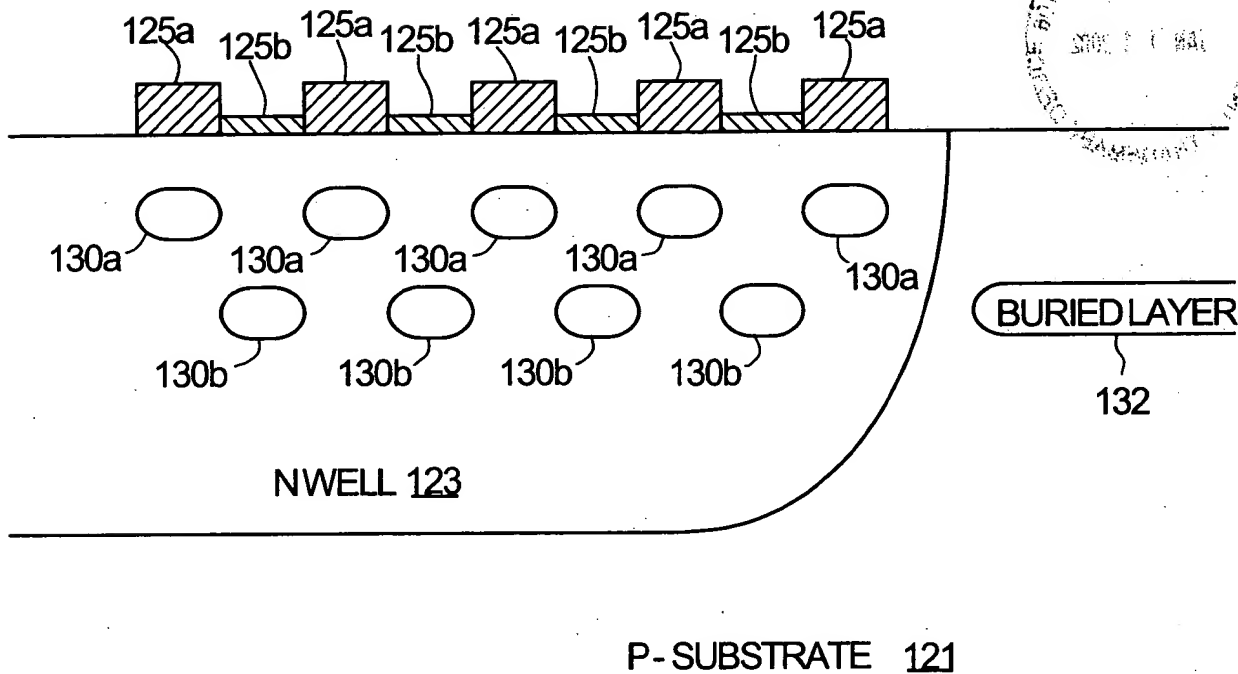


FIG. 11d

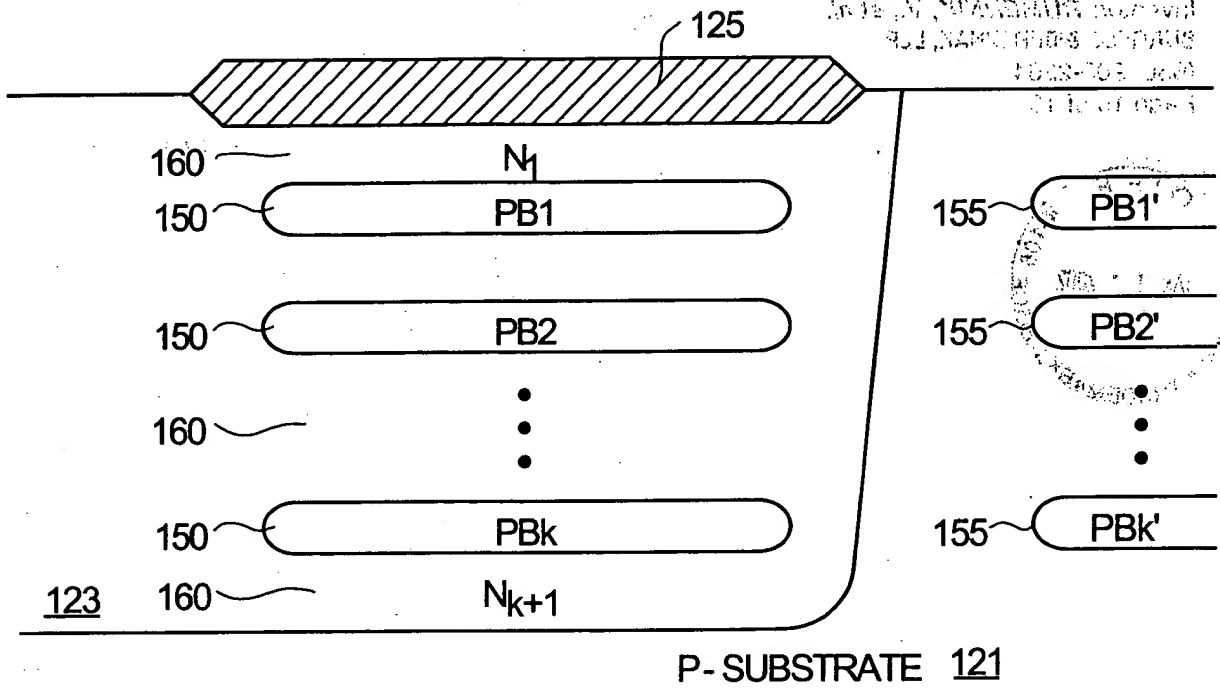


FIG. 11e

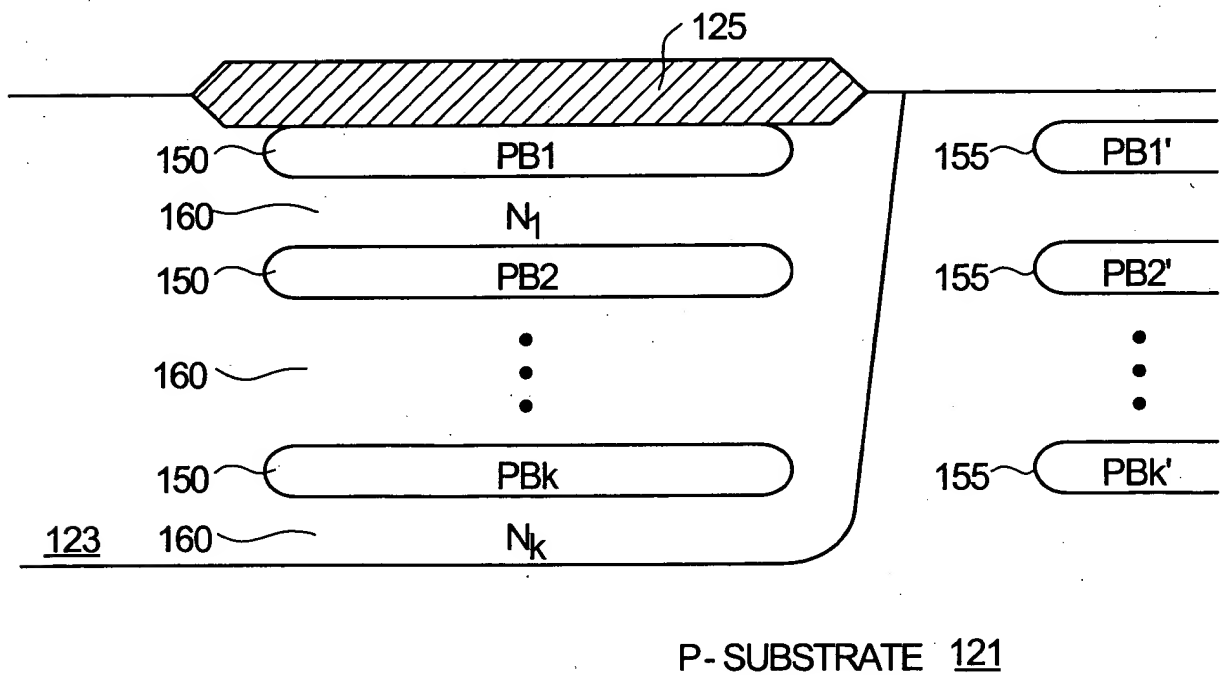


FIG. 11f

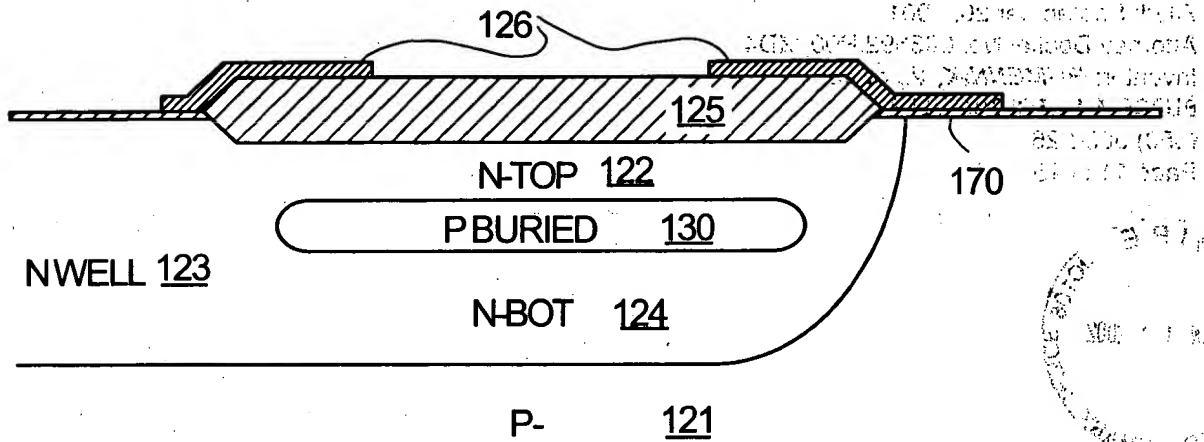


FIG. 11g

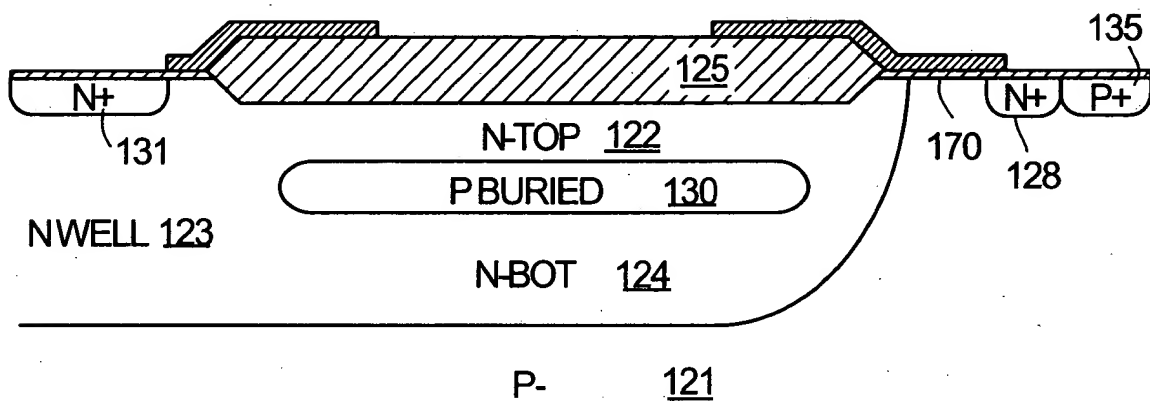


FIG. 11h

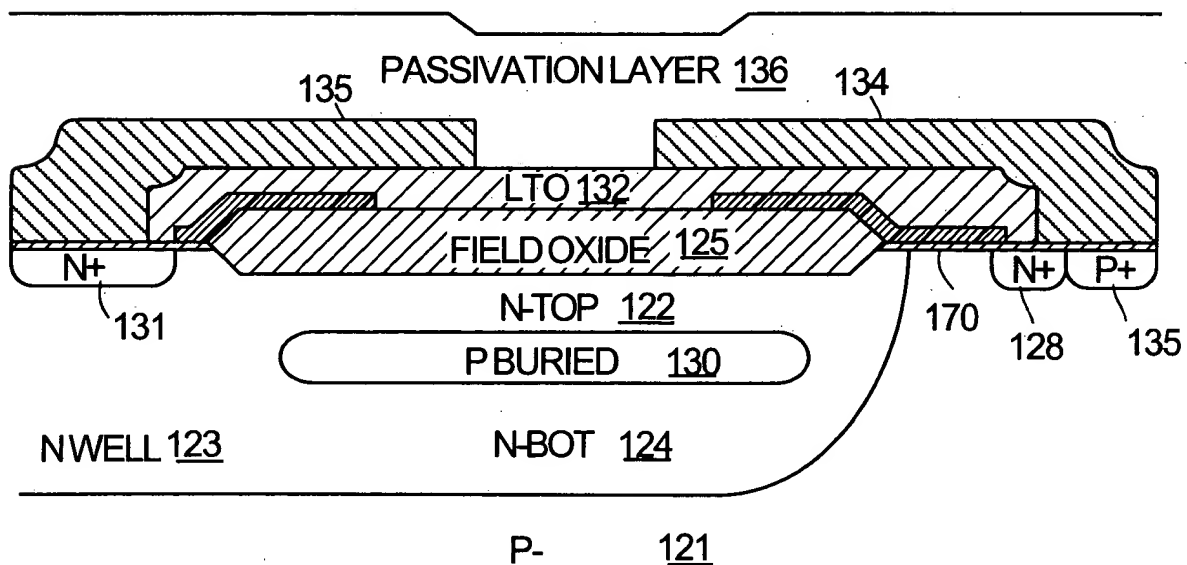


FIG. 11i

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1. The first step is to identify the problem. In this case, the problem is that the system is not working properly.



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THE H-1000 TRANSFER WITH MULTIPLE-EXPOSURE
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 Page 2 of 2
 H-1000 TRANSFER WITH MULTIPLE-EXPOSURE
 2000-10-10 10:00
 H-1000 TRANSFER WITH MULTIPLE-EXPOSURE
 2000-10-10 10:00
 H-1000 TRANSFER WITH MULTIPLE-EXPOSURE
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LOG
 (CONCENTRATION)

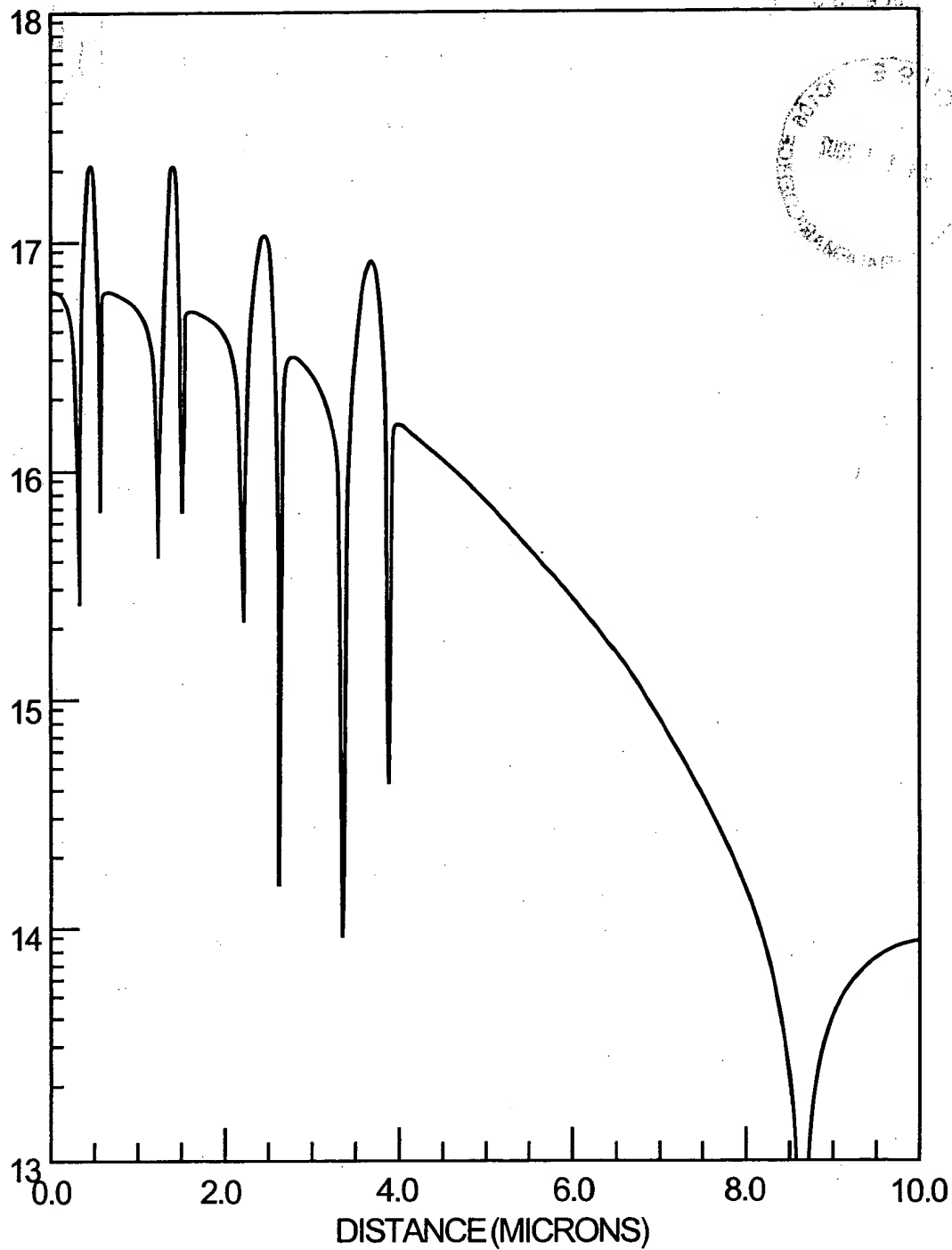


FIG. 13

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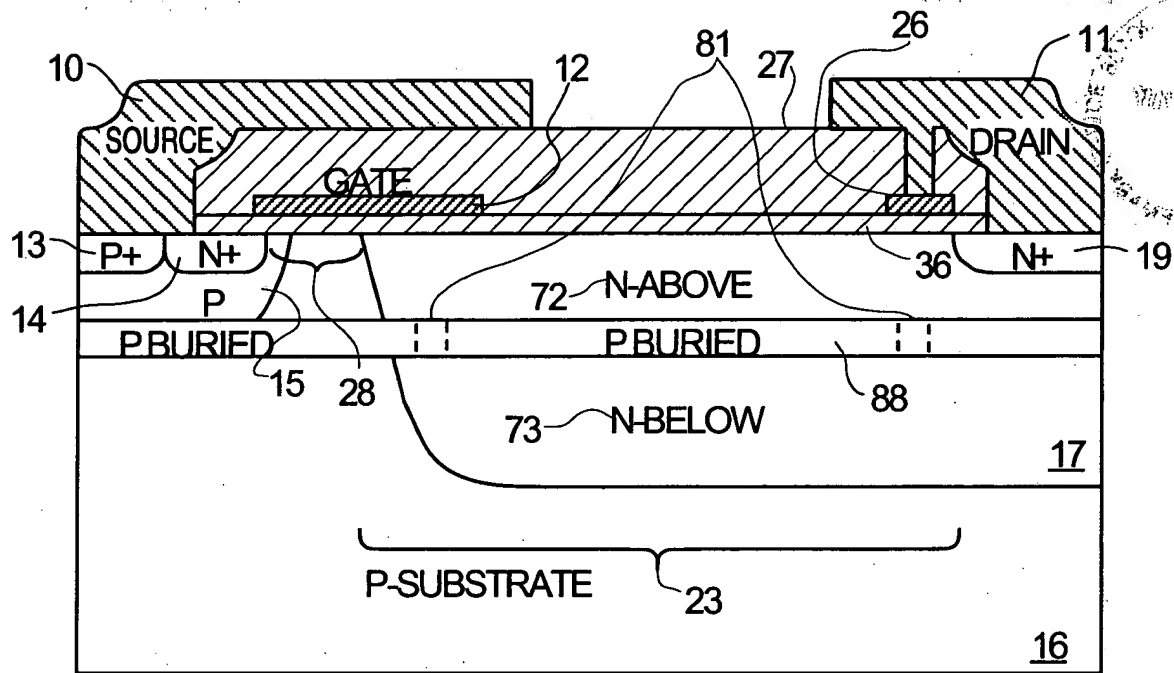


FIG. 14

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